

Search Notes

Application/Control No.

10/625,567

Examiner

Nhan T. Tran

Applicant(s)/Patent under
Reexamination

FUNAKOSHI ET AL.

Art Unit

2622

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated EAST - previously cited references were used	9/18/2007	NT